

# Rapid Quantification of Light Trapping in Bifacial Silicon Solar Cells Based on Inline Reflection Measurements

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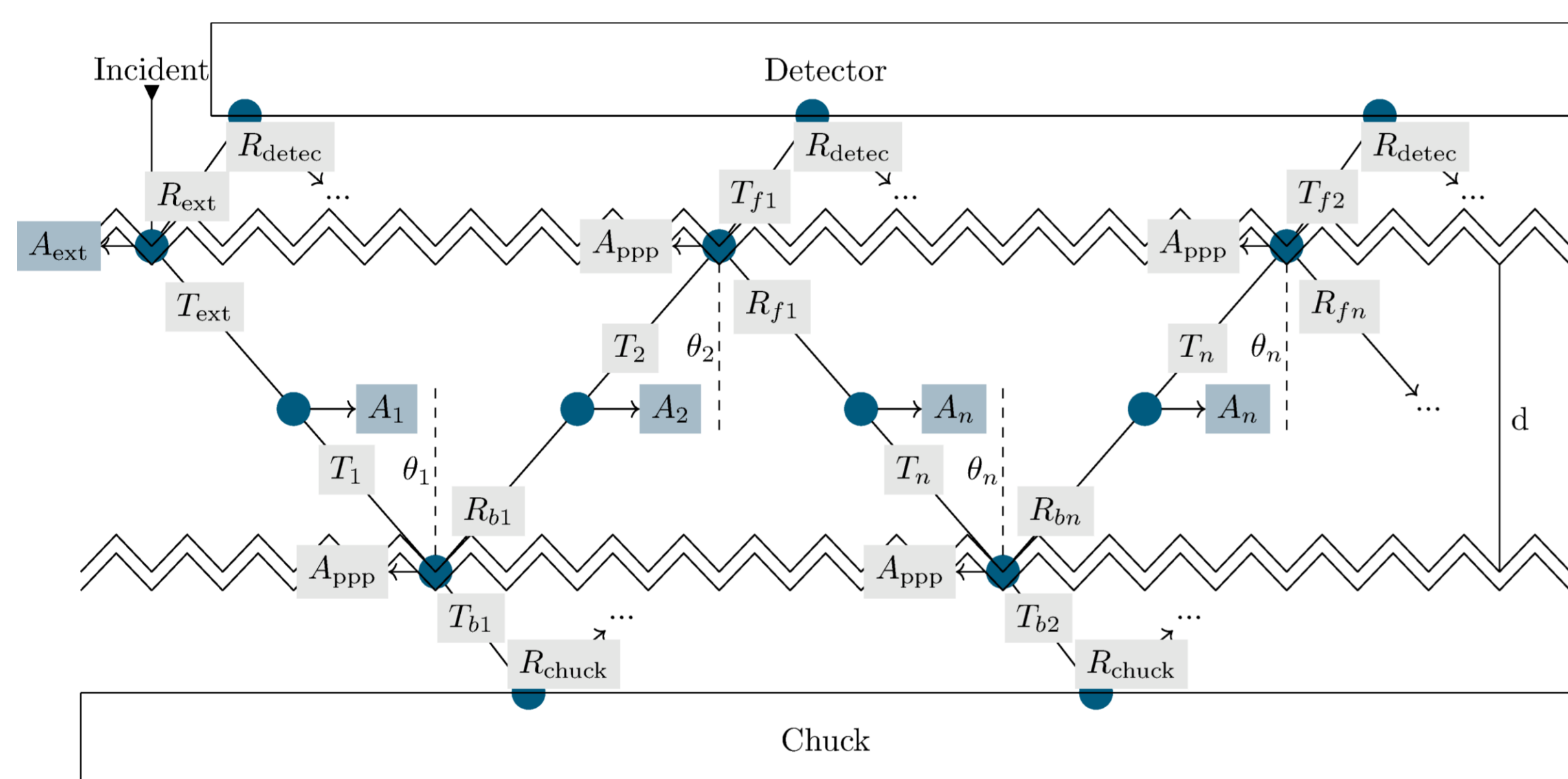
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## Introduction

- Analytical light trapping model of solar cells by Basore<sup>1</sup> and extensions<sup>2,3</sup>
  - Reflection  $R$ , transmission  $T$  and parasitic/active absorption  $pA/A$
  - Suitable for common silicon based solar cells
- Fits to simple reflectance spectra suffer from overfitting
- Fits including information on  $R$  and  $T$  more stable and robust<sup>4</sup>
  - ⇒ Inline measurements with direct model fits feasible

## Effective Optical Light Trapping

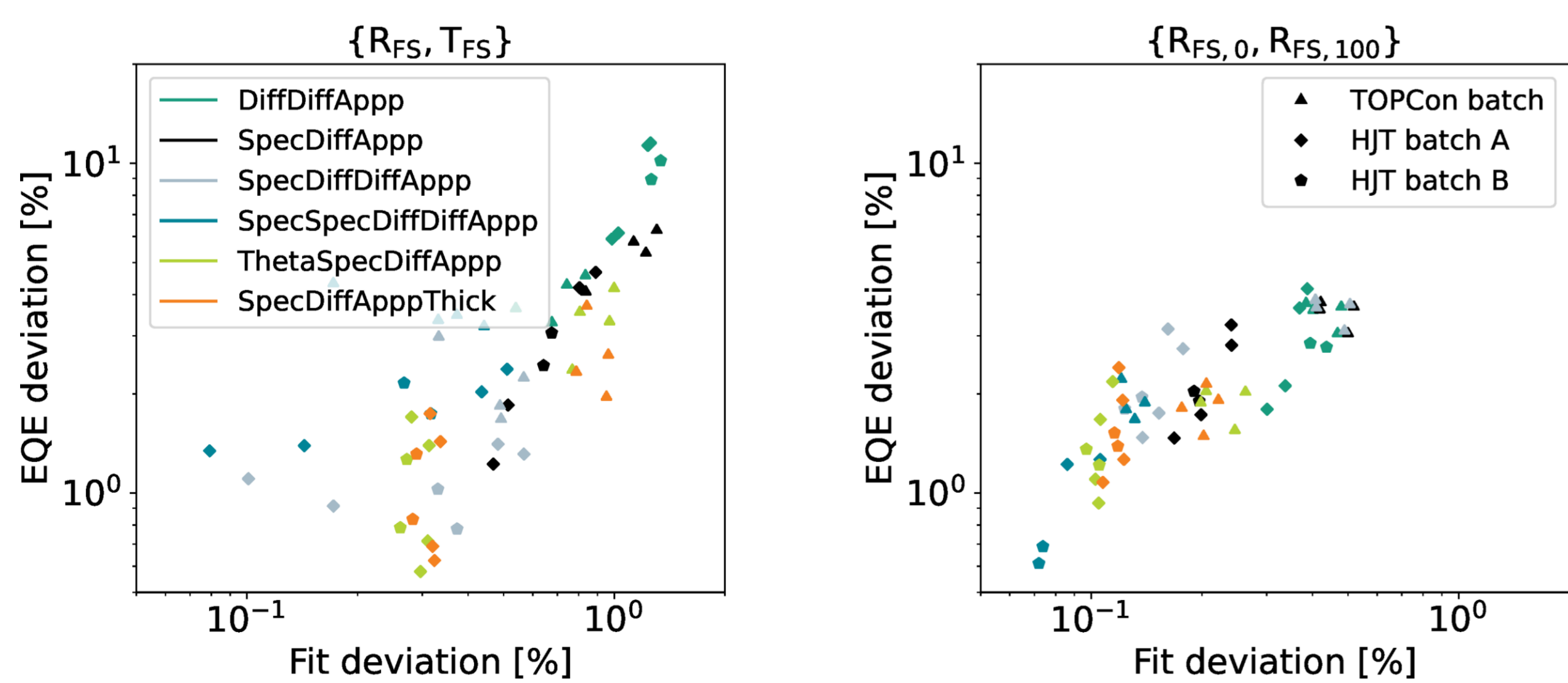
- Light absorption profile required as an input for electrical simulations
  - Used for example in PC1D, Quokka3 or PVLighthouse
- Reflection, transmission and external quantum efficiency (EQE) spectra
  - Information on light trapping at  $\lambda > 950$  nm
- Calculation time of numerical fit procedure  $t_{fit} \approx 30$  ms



Sketch of effective analytical light trapping model originally proposed by Basore<sup>1</sup>.

## Fit Accuracy Analysis and Choice of Dataset

- Measurement data sets
  - Reflectance and transmittance  $\{R_{FS}, T_{FS}\}$
  - Reflectance on black and white backgrounds  $\{R_{FS,0}, R_{FS,100}\}$
- 6 sets of free fit parameters and 10 sample from industry and Fraunhofer ISE

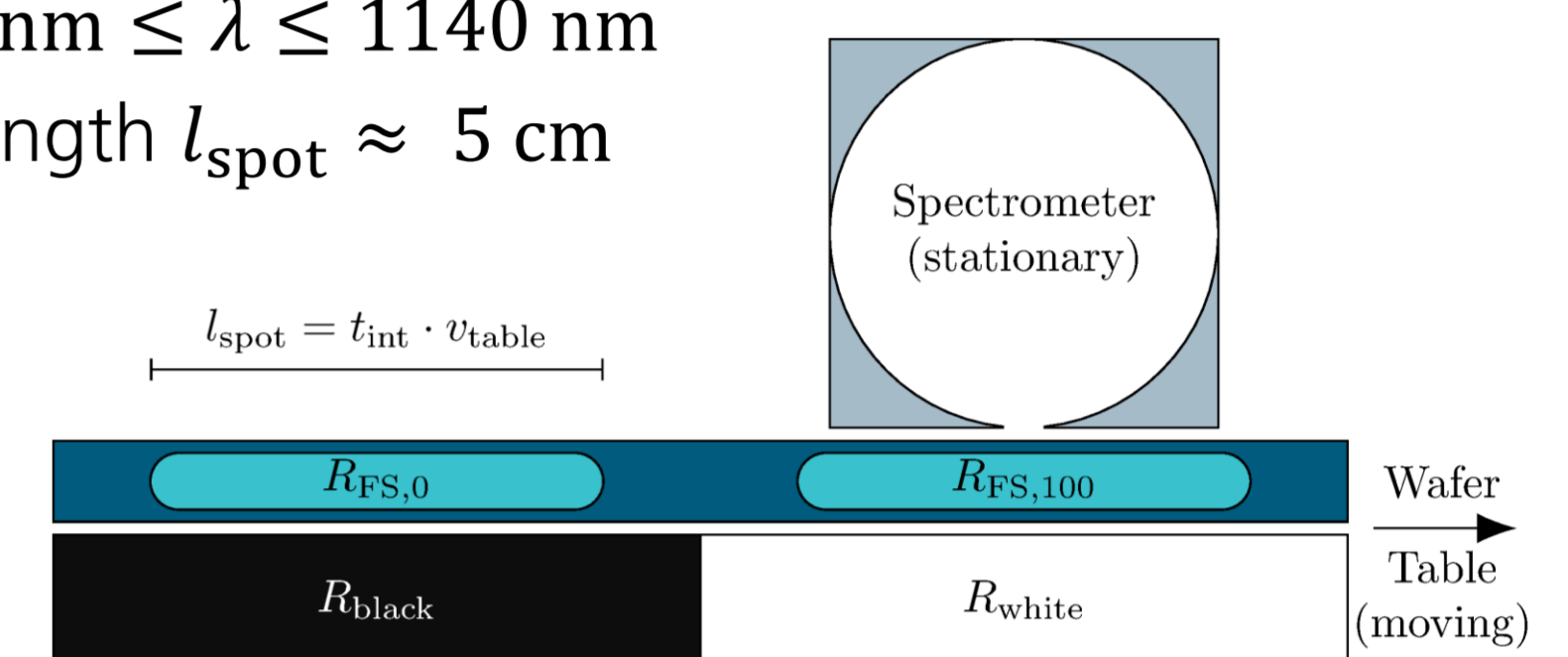


Correlation of „fit-quality“ with „EQE-accuracy“. Markers indicate cell type while colors distinguish sets of free parameters. Fits to  $\{R_{FS}, T_{FS}\}$  on the left side, and to  $\{R_{FS,0}, R_{FS,100}\}$  on the right side.

- 98<sup>th</sup> percentile of  $|\vec{V}_{meas} - \vec{V}_{model}|$  as measure of deviation
- Correlation of „fit-quality“ with deviations in EQE
  - ⇒ Two reflection spectra on black and white background constrain fits well

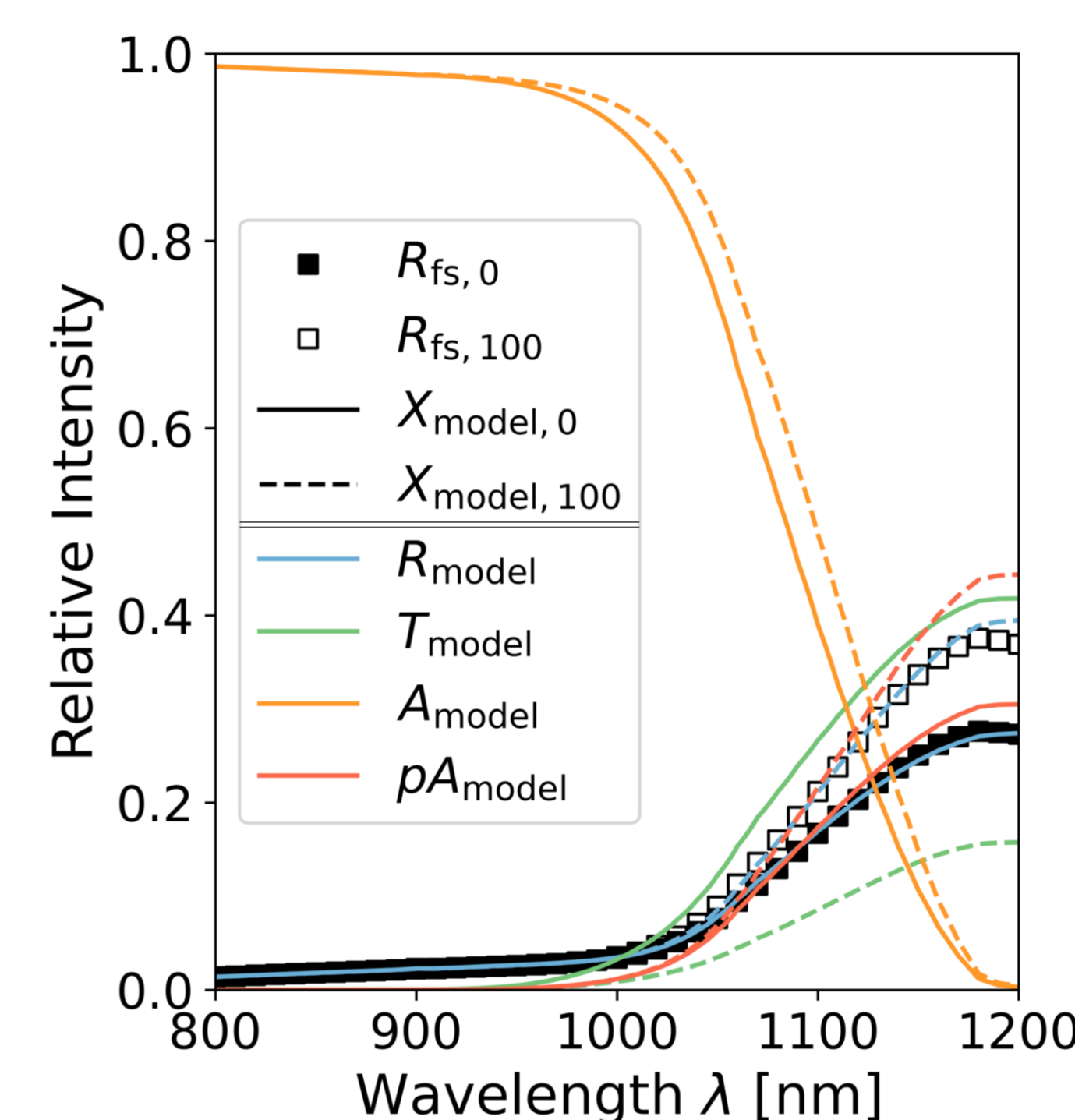
## Inline Measurement Setup

- Stationary detector with moving table
- Measurement wavelengths  $360 \text{ nm} \leq \lambda \leq 1140 \text{ nm}$
- Spot width  $w_{spot} \approx 2 \text{ cm}$  and length  $l_{spot} \approx 5 \text{ cm}$
- Integration time  $t_{int} \approx 50 \text{ ms}$
- Black and white background
  - $R_{black}(\lambda) \approx 5 \%$
  - $R_{white}(\lambda) \approx 80 \%$
- $R_{FS,0}$  and  $R_{FS,100}$  together include necessary information on transmission



## Example Fit and Inline Parameter Correlations

- Inline reflectance of 100 bifacial SHJ solar cells, M6+,  $\eta \in [22.34, 22.54] \%$
- Combined least square fit of effective model to  $R_{FS,0}$  and  $R_{FS,100}$



					$A_{ppp}$ 0.01 - 0.02
				$R_{bn}$ 0.92 - 0.94	-0.65
			$R_{in}$ 0.91 - 0.93	0.67	-0.73
		$R_{fs}$ 0.83 - 0.90	-0.36	-0.43	0.21
	$J_{gen}$ 39.36 - 39.65 mA/cm <sup>2</sup>	0.27	0.54	0.43	-0.72
$J_{sc}$ 37.43 - 37.79 mA/cm <sup>2</sup>	0.01	0.04	0.12	0.09	-0.07

Example fit to  $R_{FS,0}$  and  $R_{FS,100}$  with the corresponding modeled spectra.

Correlations of fit parameters, short circuit- and generation-current  $J_{SC}$  and  $J_{gen}$ . The transposed elements contain the correlation coefficients.

## Results

- Good convergence for all cells
  - $A_{ppp}$  as observed by Fell et al.<sup>3</sup>, and  $R_{int} \approx 0.92$  for diffuse light<sup>5</sup>
- Highest impact on  $J_{gen}$  given by parasitic absorption parameter  $A_{ppp}$
- Short circuit current  $J_{SC}$  not dominated by light trapping in example batch

## Application

- Compressed information for inline modeling and characterization

## Conclusion

- Analytical chuck extension for light trapping models introduced
- Stable model fits for reflectance on black and white backgrounds
- Method validated on 100 bifacial silicon heterojunction solar cells
- Possible application as input of inline characterization and digital twins

## References

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